

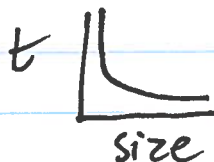
# Energy Optimization

(1)

- power is usually a hard constraint: exceeding will damage circuit  
e.g. TDP ~~to~~ thermal design power = power consumption under max theoretical load
- optimize for energy:  $E = Pt$

## Caches

- power consumption  $\propto \text{size}^2$
- ~~exe~~ execution time decreases non-linearly with size



- see Hardauts > energy MPEG energy vs cache size diagram

## Dynamic Voltage and Frequency Scaling

- most effective when dynamic power consumption dominates

- $P \propto V^2$

- ~~log~~ gate delay  $\propto V \Rightarrow f \propto V$

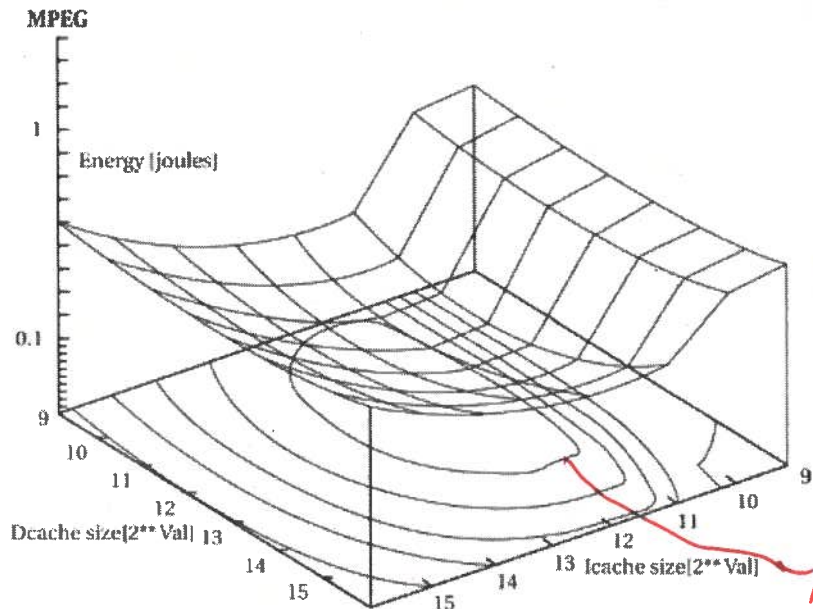
- running at a lower voltage increases energy efficiency
- generally OSs monitor workload and adjust  $V$  and  $f$
- we focus on picking  $V$  and  $f$  for an embedded application

- execution time,  $t = \frac{K}{f}$  — <sup>total</sup> PE cycles to execute application

- goal: find best  $V$  and  $f$  such that  $P < P_{\max}$  and  $t < T$   
— max execution time

# MPEG: energy consumption vs cache size

(2)

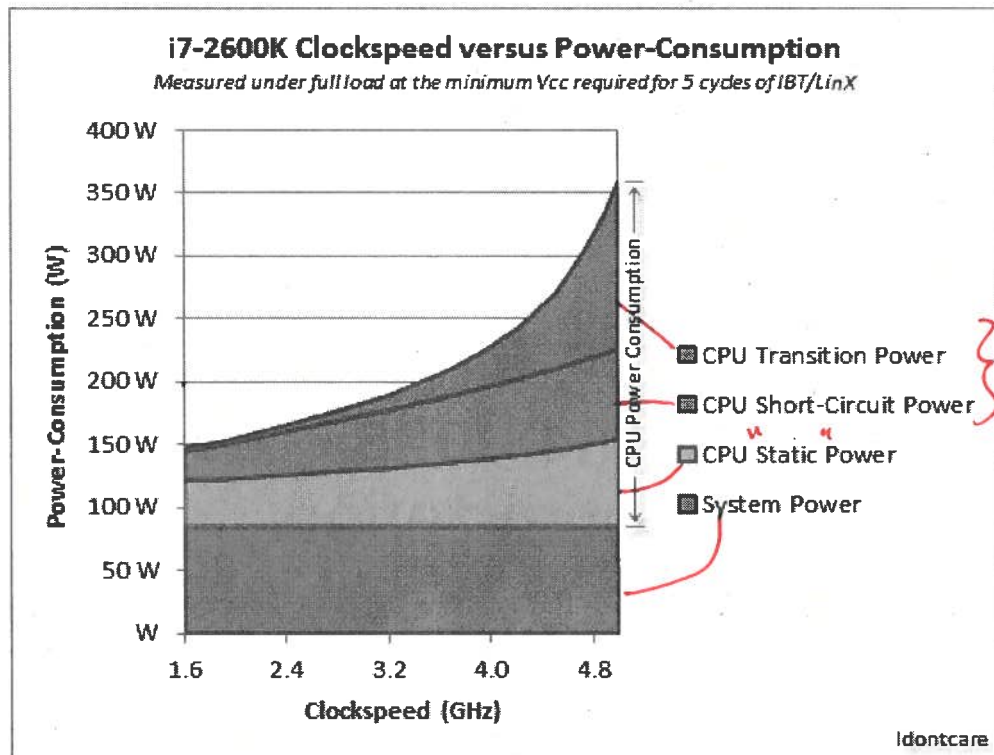


*points with same energy consumption*

R Pellizzoni (publication unknown)

$$w = R + 46.9V + 14.4f + 3.7V^{4.9}f$$

system
static
dynamic-sc
dynamic-st



R Pellizzoni (publication unknown)

# CMOS power model

- dynamic power consumption

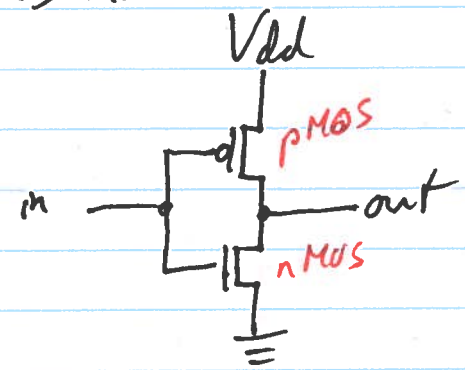
a) signal transition:  $W_{sr} = \frac{1}{2} C \times SW \times V^2 \times f$

due to output capacitance

$f$  switching rate: rate of change of logic gate outputs

b) short circuit:  $W_{sc} = E_{sc} \times SW \times f$   
CMOS Inverter

due to non-zero rise/fall times



- static power consumption

leakage current - becomes more important as device sizes decrease

e.g. subthreshold leakage through transistor independent of  $f$

- system power

losses from other components such as power supply, I/O (generally static)

- see clock speed vs power diagram

# CMOS power model

## - dynamic power consumption

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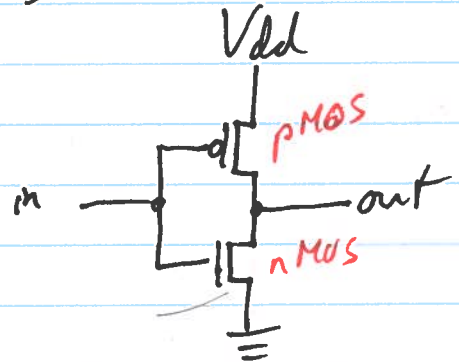
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CMOS Inverter

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leakage current - becomes more important as device sizes decrease

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## - system power

loses from other components such as power supply, I/O (generally static)

- see clock speed vs power diagram (page 2)

(5)

## Example: Battery Powered CMOS Sensor

- assume  $W_{ST} = W_{leakage}$  and  $W_{sc}$  and  $W_{sys}$  are negligible
- assume  $W_{leakage} \propto V$  dynamic static

$$E_{task} = (W_{ST} + W_{leakage}) \times t = 2wt$$

- option 1: scale frequency only ( $V$  remains unchanged)

$$f' = f/2$$

$$W_{ST}' = W_{ST}/2, W_{leakage} \text{ unchanged}, t' = 2t$$

$$E'_{task} = (W/2 + w) \times 2t = 3wt > 2wt$$

- option 2: scale voltage (requires scaling frequency)

$$V'' = V/2, f'' = f/2$$

$$W_{ST} = \frac{1}{2} C \times SW \times V^2 \times f$$

$$W_{ST}'' = \frac{1}{2} C \times SW \times \left(\frac{V}{2}\right)^2 \times \frac{f}{2} \\ = W_{ST}/8$$

$$W_{leakage}'' = W_{leakage}/2, t'' = 2t$$

$$E''_{task} = (W/8 + w/2) \times 2t = 1.25wt < 2wt$$

- need to scale both  $V$  and  $f$  to save energy

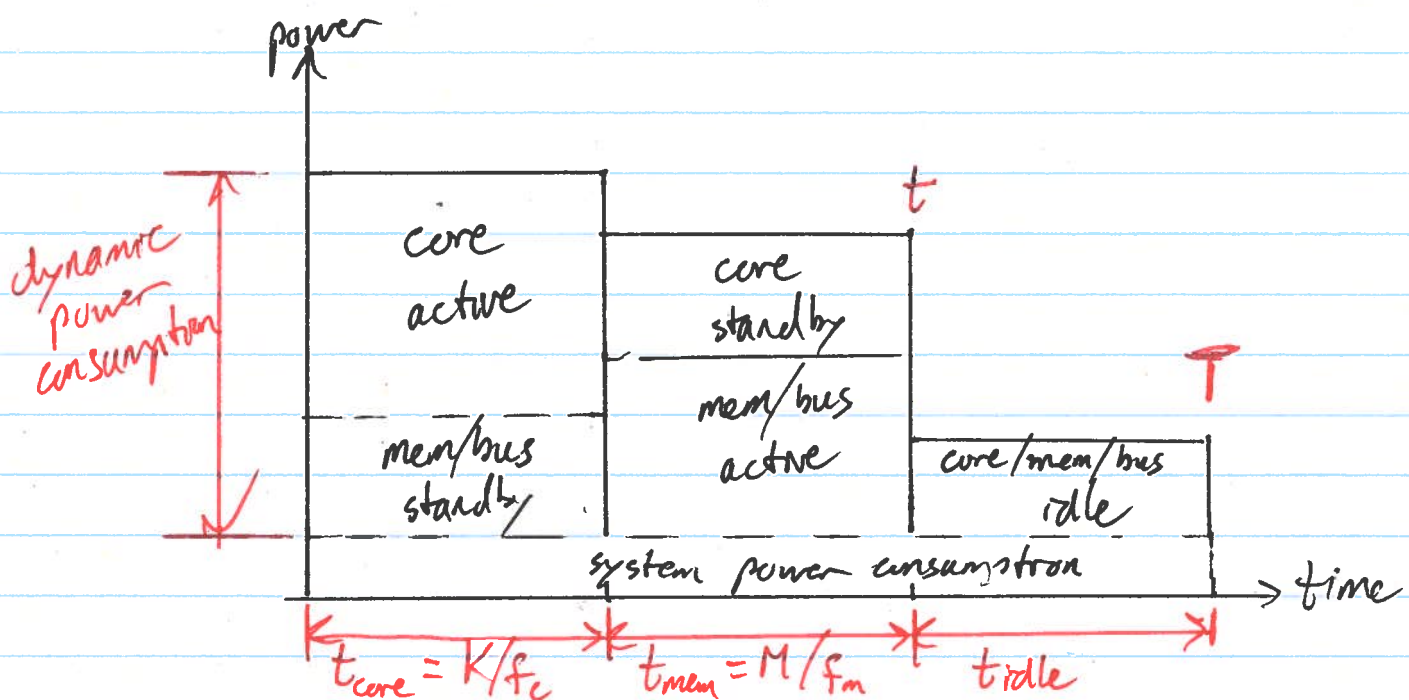


## DVFS for PE + memory

- execution time,  $t = K/f_c + M/f_m$   
 $f_c$  = core frequency,  $f_m$  = memory frequency  
*active core (PE) cycles (mem. standby)* 6  
*active memory cycles (core standby)*
- assume that bus and memory share a clock and are active/standby at the same time
- core (PE) states
  - Active - processing instructions
  - Standby - waiting for memory
  - Idle - low power mode (independent of  $V$  and  $f$ )
- use same kind of model for memory + bus
- ignore  $W_{sc}$  (dynamic-short circuit) and  $W_{leakage}$  (static) power consumption

## Task Set Power Model

- task set super period,  $T$ , ( $=$  LCM of periods)
- constraint  $t < T$



(7)

power mode continued

$E_{xy}$ :  $x = c$  (core) or  $m$  (memory)

$y = a$  (active) or  $s$  (standby)

\* the same voltage is used for all components

$$E_{\text{taskset}} = E_{ca/ms} + E_{cs/ma} + E_{\text{idle}}$$

$$= \left( \overbrace{C_{ca} \times V^2 \times f_c}^{W_{sr}} + \overbrace{C_{ms} \times V^2 \times f_m}^{W_{sr}} + \overbrace{R}^{W_{sys}} \right) \times \frac{K}{f_c} \quad (E_{ca/ms})$$

$$+ \left( C_{cs} \times V^2 \times f_c + C_{ma} \times V^2 \times f_m + R \right) \times \frac{M}{f_m} \quad (E_{cs/ma})$$

$$+ (I + R)(T - t)$$

$\underbrace{\hspace{10em}}_{\text{idle power}} \quad t_{\text{idle}}$

- see ARM926EJ-S data + graph (page 3)